

Search Notes

Application No.

09/652,159

Examiner

Vanel Frenel

Applicant(s)

LIU ET AL.

Art Unit

3626

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| West 2.0 ; Other Databases:USPAT; EPO; JPO;DERWENT WORLD PATENTS INDEX; IBM TECHNICAL DISCLOSURE BULLETINS | 10/3/2004 | V.F |
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